Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/753,976	LIEW ET AL.	
Examiner	Art Unit	
John F. Ramirez	3737	

	SEARCHED					
Class	Subclass	Date	Examiner			
378	54,56	3/3/2006	JFR			
128	660.01	3/4/2006	JFR			
			-			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Plus search	3/2/2006	JFR		
EAST Text search, backward/forward citations	3/3/2006	JFR		
Inventor's name	3/3/2006	JFR		